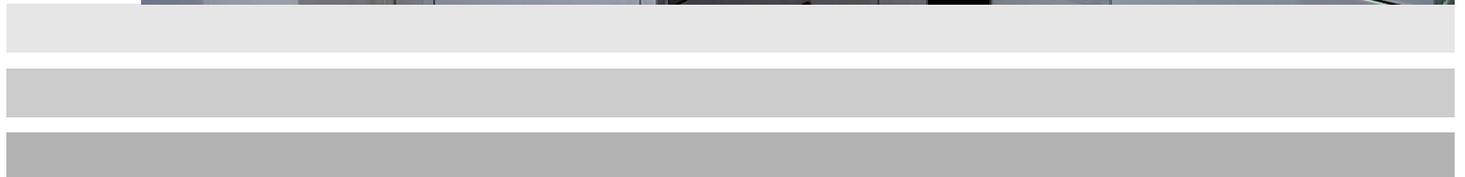


CREDEN

WIS 8000

300mm Wafer Inspection System



Product specification

Wafer size	200mm and 300mm
Cassette type	Configurable to FOUP, FOSB & Open Cassette (max 3 port)
Inspection mode	Top / back macro, micro inspection
Optical head	Flexible to configure with any major brand optical system
Macro light source	Scattered green LED and focus halogen
Wafer alignment	Non-contact laser centering
Wafer loading	R-theta robotic arm with vacuum pickup
Stage	Motorized XYZ vacuum stage controllable by joystick or recipe. With vibration isolation platform
Wafer ID reader	OCR reader or 2D matrix capability
Wafer mapping	Uploading & downloading of wafer map and edit
Image capturing	Colour CCD with image capturing
Optional item	FOV XY & Z measurement Realtime autofocus module Wafer sorter module HSMS (SEMI E13); SECS II (SEMI E5) Mini environment
Computer	Industrial base PC with touch screen LCD monitor
Software	Recipe managed by user friendly GUI software run under Win XP
Utility requirement	1Ø 230VAC. Vacuum -67Kpa
External dimension	

For further inquires, please contact:

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